

# ***METHOD FOR OPTICAL-LIGHT SCANNING OF A SPECIMEN; AND SCANNING MICROSCOPE FOR SCANNING A SPECIMEN***

## **Abstract of Disclosure**

A method and a scanning microscope for application of the method for optical-light scanning of a specimen, preferably in scanning microscopy, in particular in confocal laser scanning microscopy, the intensity of the light being regulated, is characterized, in order to optimize signal yield already during the actual data recording or measurement, in that regulation is accomplished as a function of the current focus position in the specimen region of the scanned, focused light beam.

Patent No. 4,444,444